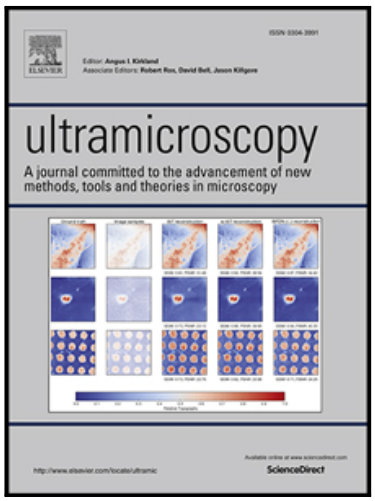

The Effect of Scanning Jitter on Geometric Phase Analysis in STEM Images

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Highlights

- Periodic jitter of electron probe can give rise to artifacts in STEM images.
- The effect of probe jitter can be revealed by geometric phase analysis.
- The probe jitter stems from the high order harmonic signal of 60 Hz AC circuits.
- A strategy to eliminate the effect of probe jitter has been proposed and tested.